Special Issue

Pattern Recognition Applications of Neural Networks and Deep Learning

Message from the Guest Editor

We are pleased to announce a call for submissions to the upcoming **Special Issue on "Pattern Recognition Applications of Neural Networks and Deep Learning"**. It aims to garner cutting-edge research and practical applications that demonstrate the power and versatility of neural networks and deep learning in solving pattern recognition problems across various domains. In recent years, neural networks—particularly deep learning architectures—have achieved unprecedented success in pattern recognition tasks, ranging from image and speech processing to biometrics, natural language understanding, and medical diagnostics. This Special Issue seeks high-quality, original research papers that explore innovative methodologies, applications, and theoretical advancements in this field.

Guest Editor

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Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

Editor-in-Chief

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